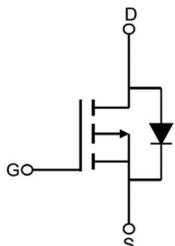


## Description

<b>Features</b> <ul style="list-style-type: none"> <li>● <math>V_{DS} = -40V</math>, <math>I_D = -40A</math></li> <li>    <math>R_{DS(ON)} &lt; 13m\Omega</math> @ <math>V_{GS} = -10V</math></li> <li>    <math>R_{DS(ON)} &lt; 22m\Omega</math> @ <math>V_{GS} = -4.5V</math></li> <li>● Advanced Trench Technology</li> <li>● Excellent <math>R_{DS(ON)}</math> and Low Gate Charge</li> <li>● Lead free product is acquired</li> </ul>	<b>Application</b> <ul style="list-style-type: none"> <li>● PWM Applications</li> <li>● Load Switch</li> <li>● Power Management</li> </ul> <p style="text-align: center;">100% UIS 100% <math>\Delta V_d</math>s</p>
 <p>TO-252</p>	 <p>Schematic Diagram</p>

## Package Marking and Ordering Information

Device Marking	Device	OUTLINE	Device Package	Reel Size	Reel (PCS)	Per Carton (PCS)
VSM40P04-T2	VSM40P04	TAPING	TO-252	13inch	2500	25000

## Absolute Maximum Ratings (T<sub>C</sub>=25°C unless otherwise specified)

Symbol	Parameter	Max.	Units
V <sub>DSS</sub>	Drain-Source Voltage	-40	V
V <sub>GSS</sub>	Gate-Source Voltage	±20	V
I <sub>D</sub>	Continuous Drain Current	T <sub>C</sub> = 25°C	-40
		T <sub>C</sub> = 100°C	-26
I <sub>DM</sub>	Pulsed Drain Current <sup>note1</sup>	-160	A
E <sub>AS</sub>	Single Pulsed Avalanche Energy <sup>note2</sup>	144	mJ
P <sub>D</sub>	Power Dissipation	41.6	W
R <sub>θJC</sub>	Thermal Resistance, Junction to Case	3.6	°C/W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range	-55 to +175	°C

**Electrical Characteristics** ( $T_J=25^{\circ}\text{C}$  unless otherwise specified)

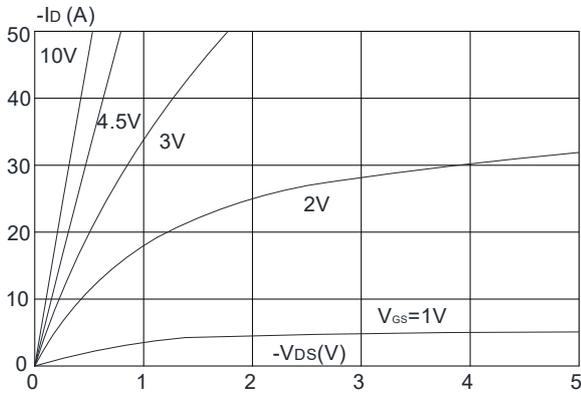
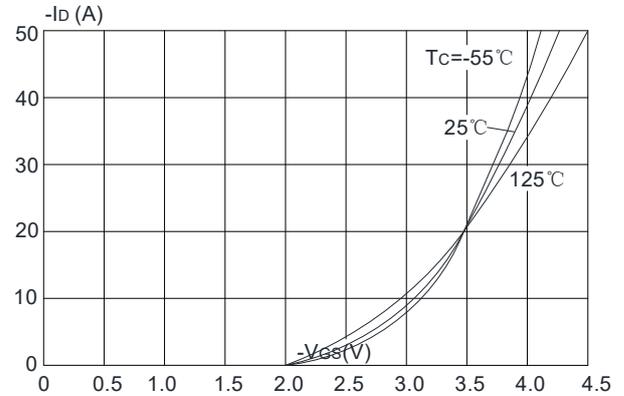
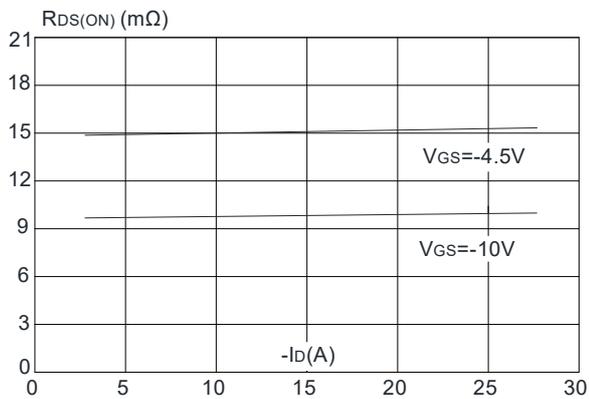
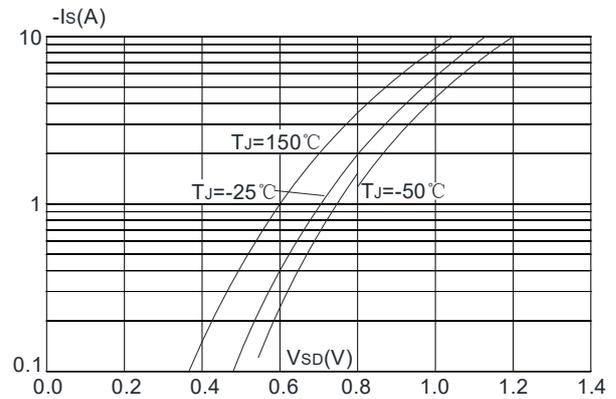
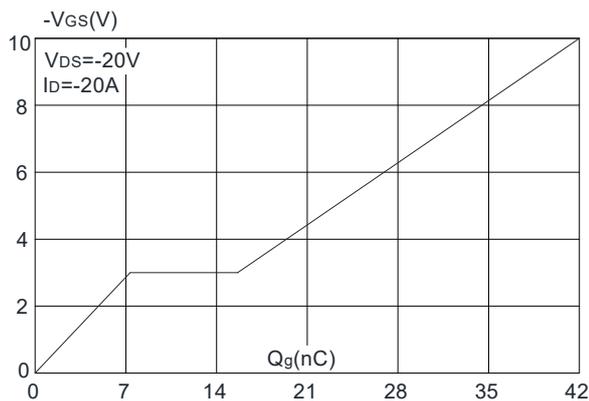
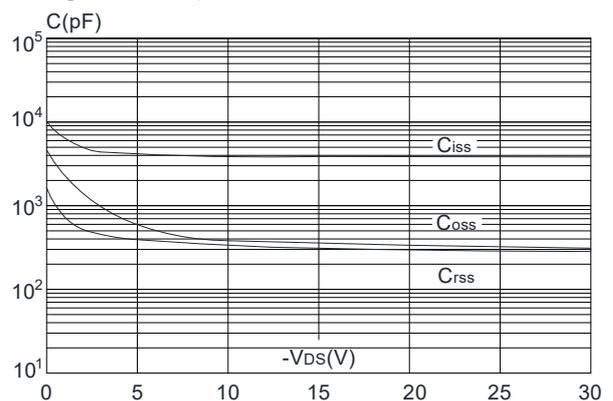
Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
<b>Off Characteristic</b>						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=-250\mu A$	-40	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=-40V, V_{GS}=0V$	-	-	-1	$\mu A$
$I_{GSS}$	Gate to Body Leakage Current	$V_{DS}=0V, V_{GS}=\pm 20V$	-	-	$\pm 100$	nA
<b>On Characteristics</b>						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu A$	-1.0	-1.7	-2.5	V
$R_{DS(on)}$	Static Drain-Source on-Resistance <small>note3</small>	$V_{GS}=-10V, I_D=-20A$	-	10	13	m $\Omega$
		$V_{GS}=-4.5V, I_D=-10A$	-	15	22	
<b>Dynamic Characteristics</b>						
$C_{iss}$	Input Capacitance	$V_{DS}=-20V, V_{GS}=0V,$ $f=1.0MHz$	-	3800	-	pF
$C_{oss}$	Output Capacitance		-	329	-	pF
$C_{rss}$	Reverse Transfer Capacitance		-	289	-	pF
$Q_g$	Total Gate Charge	$V_{DS}=-20V, I_D=-20A,$ $V_{GS}=-10V$	-	42	-	nC
$Q_{gs}$	Gate-Source Charge		-	7.3	-	nC
$Q_{gd}$	Gate-Drain("Miller") Charge		-	8.5	-	nC
<b>Switching Characteristics</b>						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD}=-20V, I_D=-20A,$ $V_{GS}=-10V, R_{GEN}=2.5\Omega$	-	10	-	ns
$t_r$	Turn-on Rise Time		-	21	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	53	-	ns
$t_f$	Turn-off Fall Time		-	29	-	ns
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_S$	Maximum Continuous Drain to Source Diode Forward Current		-	-	-40	A
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current		-	-	-160	A
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS}=0V, I_S=-30A$	-	-0.8	-1.2	V
$t_{rr}$	Reverse Recovery Time	$V_{GS}=0V, I_S=-30A,$ $di/dt=100A/\mu s$	-	39	-	ns
$Q_{rr}$	Reverse Recovery Charge		-	42	-	nC

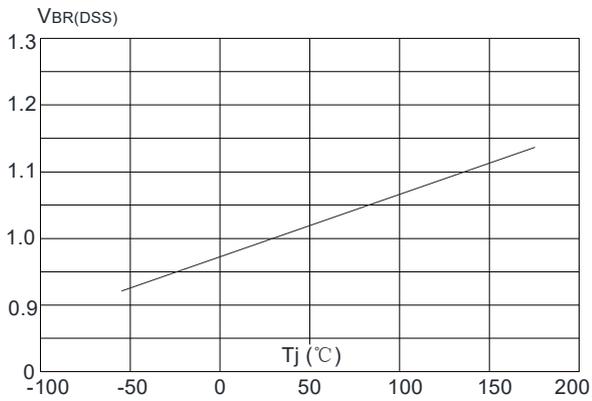
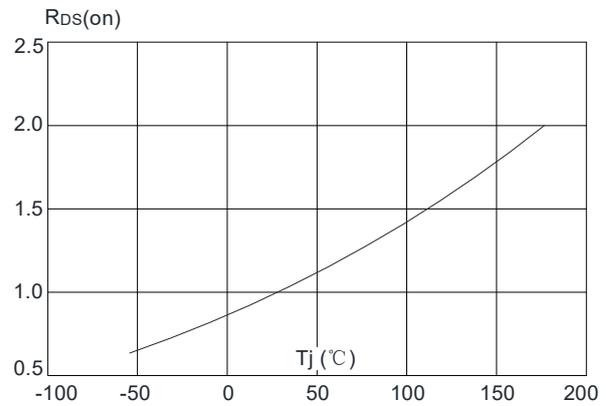
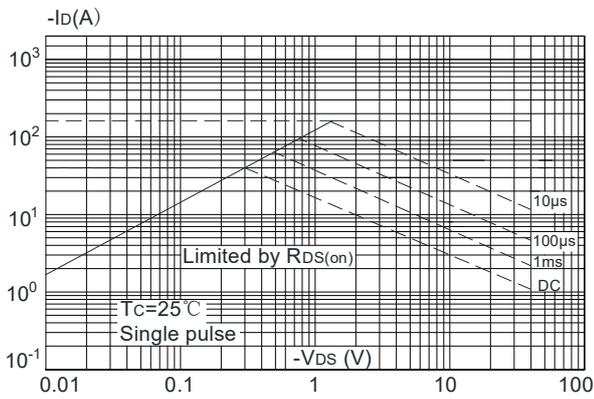
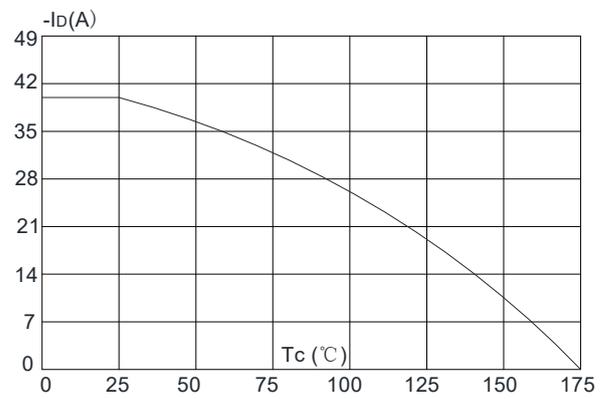
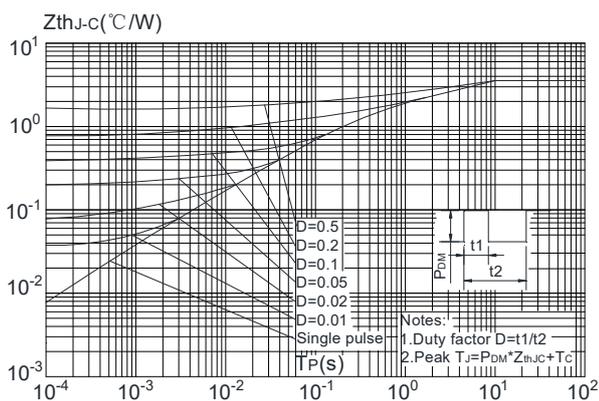
Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

 2. EAS condition:  $T_J=25^{\circ}\text{C}$ ,  $V_{DD}=-20V$ ,  $V_G=-10V$ ,  $L=0.5mH$ ,  $R_G=25\Omega$ ,  $I_{AS}=-24A$ 

 3. Pulse Test: Pulse Width $\leq 300\mu s$ , Duty Cycle $\leq 2\%$

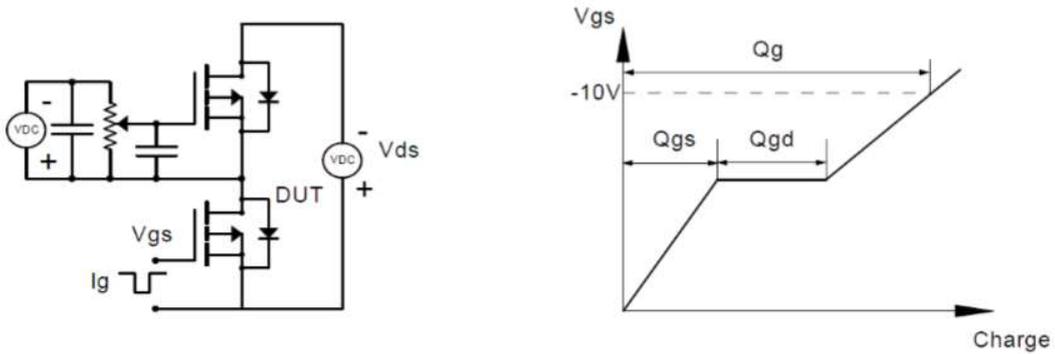
## Typical Performance Characteristics

**Figure 1: Output Characteristics**

**Figure 2: Typical Transfer Characteristics**

**Figure 3: On-resistance vs. Drain Current**

**Figure 4: Body Diode Characteristics**

**Figure 5: Gate Charge Characteristics**

**Figure 6: Capacitance Characteristics**


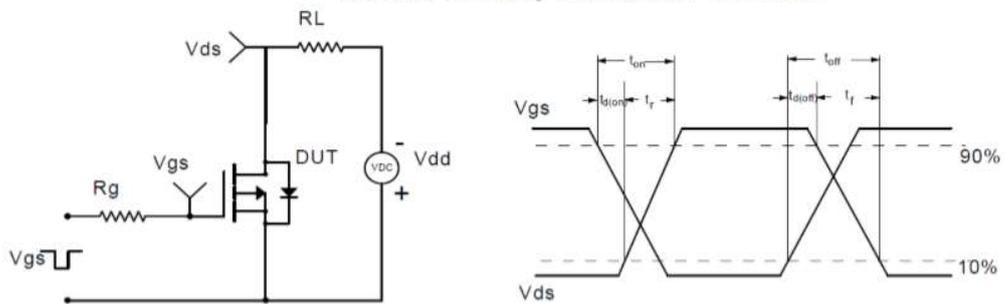
**Figure 7: Normalized Breakdown Voltage vs. Junction Temperature**

**Figure 8: Normalized on Resistance vs. Junction Temperature**

**Figure 9: Maximum Safe Operating Area**

**Figure 10: Maximum Continuous Drain Current vs. Case Temperature**

**Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case**


## Test Circuit

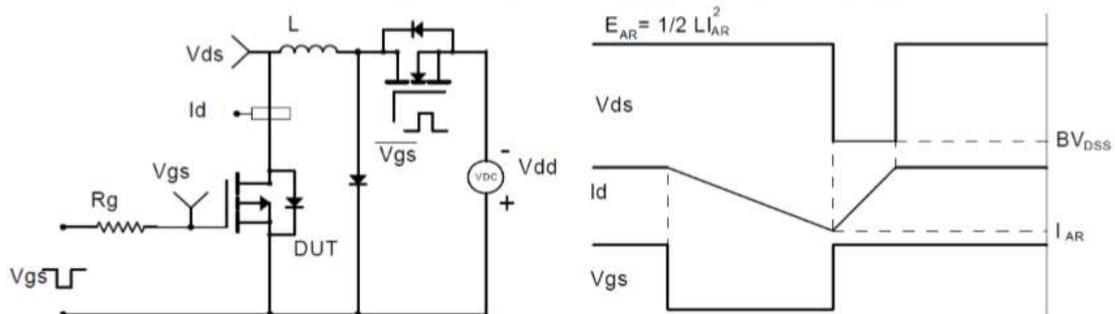
### Gate Charge Test Circuit & Waveform



### Resistive Switching Test Circuit & Waveforms



### Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



### Diode Recovery Test Circuit & Waveforms

